TOSHIBA Photocoupler GaAlAs Ired & Photo-IC

TLP114A

Digital Logic Isolation.

Line Receiver.

Power Supply Control Feedback Control.

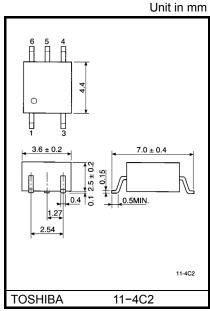
Switching Power Supply.

Transistor Inverter.

The TOSHIBA mini flat coupler TLP114A is a small outline coupler, suitable for surface mount assembly.

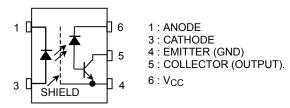
TLP114A consists of a high output power GaA ℓ As light emitting diode, optically coupled to a high speed detector of one chip photodiode-transistor.

- Isolation voltage: 3750 Vrms (min.)
- Switching speed: $t_{pHL} = 0.8\mu s$, $t_{pLH} = 0.8\mu s$ (max.) ($R_L = 1.9 \text{ k}\Omega$)
- TTL compatible
- UL recognized: UL1577, file no. E67349

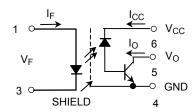


Weight: 0.09g

Pin Configuration (top view)



Schematic



TLP114A

Absolute Maximum Ratings (Ta = 25°C)

	Characteristic		Symbol	Rating	Unit
TDE	Forward current	(Note 1)	lF	20	mA
	Pulse forward current	(Note 2)	I _{FP}	40	mA
	Peak transient forward current	(Note 3)	I _{FPT}	1	Α
	Reverse voltage		V_{R}	5	V
	Output current		IO	8	mA
ō	Peak output current		I _{OP}	16	mA
Detector	Supply voltage		V _{CC}	-0.5~30	V
۵	Output voltage		Vo	-0.5~20	V
	Output power dissipation	(Note 4)	PO	100	mW
Оре	Operating temperature range		T _{opr}	-55~100	°C
Sto	Storage temperature range		T _{stg}	-55~125	°C
Lea	Lead solder temperature(10 sec.)		T _{sol}	260	°C
	Isolation Voltage (AC,1 min., R.H.≤ 60°%) (Note 5)		BVS	3750	Vrms

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

- (Note 1) Derate 0.36mA / °C above 70°C.
- (Note 2) 50% duty cycle, Ims pulse width.

Derate 0.72mA / °C above 70°C.

- (Note 3) Pulse width≤ 1µs, 300pps.
- (Note 4) Derate 1.8mW / $^{\circ}$ C above 70 $^{\circ}$ C.



Electrical Characteristics (Ta = 25°C)

Characteristic		Symbol	Test Condition	Min.	Тур.	Max.	Unit	
TDE	Forward voltage	V _F	I _F = 16mA	1.22	1.42	1.72	V	
	Forward voltage temperature coefficient	ΔV _F / ΔTa	I _F = 16mA	_	-2	_	mV /°C	
	Reverse current	I _R	V _R = 3V	_	_	10	μΑ	
	Capacitance between terminals	C _T	V _F = 0, f = 1MHz	_	30	_	pF	
Detector	High level output current	I _{OH} (1)	$I_F = 0mA, V_{CC} = V_O = 5.5V$	_	3	500	nA	
		I _{OH} (2)	I _F = 0mA, V _{CC} = 30V V _O = 20V	_	_	5	μА	
		Іон	I _F = 0mA, V _{CC} = 30V V _O = 20V, Ta = 70°C	_	1	50		
	High level supply current	Іссн	I _F = 0mA, V _{CC} = 30V		0.01	1	μΑ	
Coupled	Current transfer ratio	I _O / I _F	$I_F = 16\text{mA}, V_{CC} = 4.5\text{V}$ $V_{O} = 0.4\text{V}$	20	_	_	%	
	Low level output voltage	V _{OL}	$I_F = 16\text{mA}, V_{CC} = 4.5\text{V}$ $I_O = 2.4 \text{ mA}$	_	_	0.4	V	
	Isolation resistance	R _S	R.H.≤ 60%, V _S = 500V (Note 5)	5×10 ¹⁰	10 ¹⁴		Ω	
	Stray capacitance between input to output	C _S	V _S = 0, f = 1MHz (Note 5)	_	0.8	_	pF	

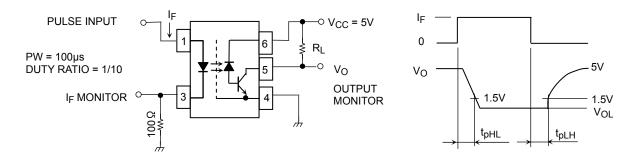
Switching Characteristics (Ta = 25°C, VCC = 5V)

Characteristic	Symbol	Test Cir– cuit	Test Condition	Min.	Тур.	Max.	Unit
Propagation delay time (H→ L)	t _{pHL}	1	$I_F = 0 \rightarrow 16 \text{mA}$ $V_{CC} = 5V, R_L = 1.9 \text{k}\Omega$	_	_	0.8	μs
Propagation delay time (L→ H)	t _{pLH}	1	IF = 16→ 0mA V_{CC} = 5V, R _L = 1.9kΩ	_	_	0.8	μs
Common mode transient immunity at high output level	СМН	2	$I_F = 0$ mA, $V_{CM} = 400V_{p-p}$ $R_L = 4.1$ k Ω	5000	10000	_	V / µs
Common mode transient immunity at low output level	C _{ML}	2	$I_F = 16\text{mA},$ $V_{CM} = 400V_{p-p}$ $R_L = 4.1\text{k}\Omega$	-5000	-10000	_	V / µs

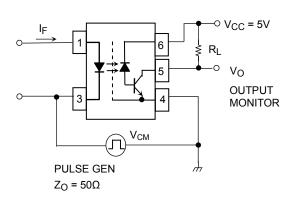
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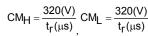
- (Note 5) Device considered a two–terminal device: Pins 1 and 3 shorted together, and pins 4, 5 and 6 shorted together.
- (Note 6) Maximum electrostatic discharge voltage for any pins: 100V(C=200pF, R=0)

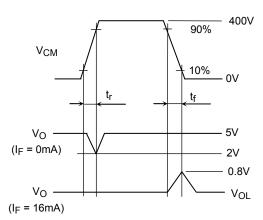
Test Circuit 1: Switching Time Test Circuit

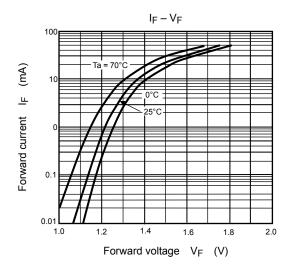


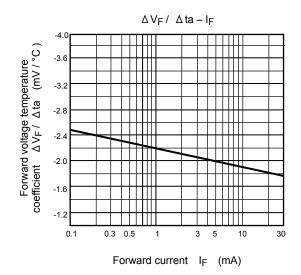
Test Circuit =2: Common Mode Transient Immunity Test Circuit

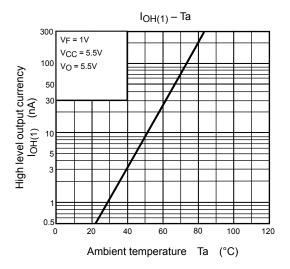


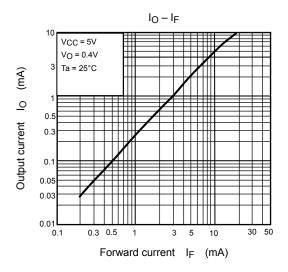


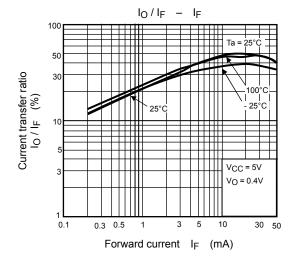


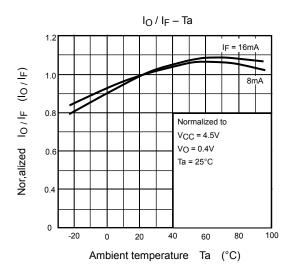




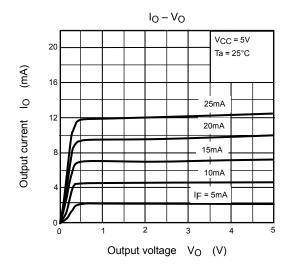


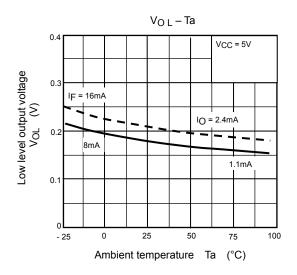


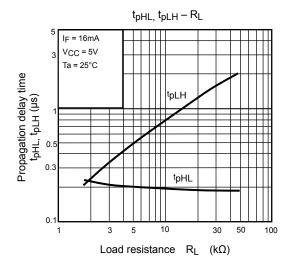


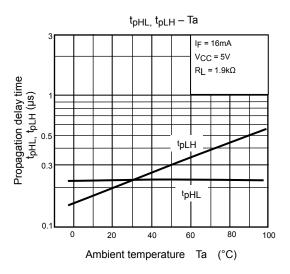


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